H idden Errors in Simulations and the Quality of P seudorandom N umbers

In a recent letter Ferrenberg et al. (FLW) [1] present intriguing results arising from combinations of some random number generators and M onte C arlo acceleration algorithm s. In particular, they observe system atic errors when the W ol algorithm [2] is used at T_c in the 2 d Ising m odel. As an explanation of this, they propose that subtle correlations arise in the random number sequences, in the sense that the higher order bits of the random numbers are correlated.

We have recently carried out extensive statistical, bit level, and visual tests for several commonly used pseudorandom number generators in physics applications [3]. Two of these were used in Ref. 1, namely R250 [4] and CONG [5]. Using the W ol algorithm FLW discovered problem swith R250, but not with CONG. Thus, our test results bear direct relevance to the existence of possible problem s, and di erences between these two algorithm s.

To directly probe the correlations between each bit of consecutive pseudorandom numbers, we have perform ed two quantitative tests. The rst one is an extended version of the m-tuple test [6]. The second test was based on the range of binary random matrices [7]. In Table 1 we present a summary of the results for each of the 31 signi cant bits from random numbers generated by R250 and CONG. Our results indicate no bit level correlations in CONG. The same is true for R250, provided it is properly initialized. This is demonstrated in Table 2, where R250 was initialized by a lagged F ibonacci generator RAN 3 [8], which contains several correlated bits, including ve of the most signi cant ones. A s seen in the results, correlations from RAN 3 transform into R250.

Our results thus indicate that the problem s observed in Ref. 1 have no simple explanation in term s of bit level correlations. We note that both R 250 and CONG were also subjected to an array of statistical tests [3,5], in which neither of them

show ed any particular weaknesses. However, our 2 d visual tests did reveal a periodic spatial ne structure in CONG, a result not unexpected with this type of algorithm [3]. Yet, no problem s with CONG were reported by FLW. Since their results presently have no clear explanation, we wholeheartedly agree with them on the importance of careful physical tests [3] before a particular "good quality" generator is chosen for simulations.

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Table Captions:

Random	Failing bits	Failing bits
num ber	in the	in the
generator	m -tuple test	random matrix test
R 250	none	none
CONG	none	none

Table 1. The results of an extended m-tuple test with parameters m = t = 3, and a test using 2 2 random matrices. In these tests R 250 was initialized by CONG.

R andom	Failing bits	Failing bits
num ber	in the	in the
generator	m-tuple test	random matrix test
R 250	1-2,27-31	1,27-31
RAN3	1 - 5 , 25 - 30	1-5,26-30

Table 2. The results of bit level tests for R 250 initialized by RAN3.